



17w

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the application of

Yehiel Gotkis

Application No. 10/810,209

Filed: March 26, 2004

For: METHOD AND APPARATUS FOR
MEASUREMENT OF THIN FILMS AND RESIDUES
ON SEMICONDUCTOR SYBSTRATES

) Examiner: Unassigned
)
) Art Unit: 1765
)
) Docket No. LAM2P466
)
) Date: September 1, 2005

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on September 1, 2005.

Signed: _____
Kay Harlow

**INFORMATION DISCLOSURE STATEMENT
UNDER 37 CFR §§1.56 AND 1.97(e)**

Commissioner of Patents and Trademarks
Alexandria, VA 22313-1450

Dear Sir:

Enclosed is a PTO Form 1449 listing U.S. patents and foreign patents to be made of record. Applicant is hereby submitting a copy of the cited foreign patent. The references listed in the attached PTO Form 1449 may be material to examination of the above-identified patent application. The Examiner is requested to make these citations of official record in this application.

The undersigned hereby certifies that these references were cited in a Search Report from a foreign patent office less than three months before the filing date of the present Information Disclosure Statement. A copy of the Search Report is enclosed herewith. Accordingly, it is respectfully submitted that no fee is due in conjunction with the filing of this IDS.

This Information Disclosure Statement is not to be construed as a representation that a search has been made, that additional information material to the examination of this application does not exist, or that these references indeed constitute prior art.

If the Commissioner should determine that additional fees are required for filing the present Information Disclosure Statement, the Commissioner is hereby authorized to charge any such fees to our deposit account number 50-0805 (Order No. LAM2P466). A copy of this sheet is enclosed.

Respectfully submitted,
MARTINE PENILLA & GENCARELLA, LLP

Albert S. Penilla, Esq.
Reg. No. 39,487

710 Lakeway Drive, Suite 200
Sunnyvale, CA 94085
(408) 774-6903
Customer Number 25920

Attorney Docket No. LAM2P466



| | | |
|--|---------------------|------------|
| Form 1449 (Modified) Information Disclosure Statement By Applicant (Use Several Sheets if Necessary) | Attorney Docket No: | U.S. |
| | LAM2P466 | 10/810,209 |
| | Applicant: | |
| | Y. Gotkis | |
| | Filing Date: | Group: |
| | March 26, 2004 | 1765 |

U.S. Patent Documents

| Examiner Initial | No. | Patent No. | Date | Patentee | Class | Sub-class |
|------------------|-----|--------------------|---------|---------------|-------|-----------|
| | A | US 2002/0054290 A1 | 05/2002 | Vurens et al. | 356 | 369 |
| | B | 5,898,181 | 04/1999 | Vurens | 250 | 559.28 |
| | C | | | | | |
| | D | | | | | |
| | E | | | | | |
| | F | | | | | |
| | G | | | | | |
| | H | | | | | |
| | I | | | | | |

Foreign Patent or Published Foreign Patent Application

| Examiner Initial | No. | Document No. | Date | Country or Patent Office | Class | Sub-class | Translation | |
|------------------|-----|--|----------|--------------------------|-------|-----------|-------------|----|
| | | | | | | | Yes | No |
| | J | 2000028748 <i>Patent Abstracts of Japan</i> | 28/01/00 | EPO | G01V | 8/12 | | X |
| | K | WO 00/12958 | 09/03/00 | WIPO | G01B | 9/02 | | X |
| | L | 0 296 365 A1 | 28/12/88 | EPO | G01T | 1/29 | | X |
| | M | WO 99/08066 | 18/02/99 | WIPO | G01B | 9/02 | | X |
| | N | | | | | | | |

Other Documents

| Examiner Initial | No. | Author, Title, Date, Place (e.g. Journal) of Publication |
|------------------|-----|--|
| | O | |
| | | |
| | P | |
| | | |
| | | |
| Examiner | | Date Considered |
| | | |

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.